

**IPC-6012D**  
**2015 - September**

**Qualification and Performance  
Specification for Rigid  
Printed Boards**

Supersedes IPC-6012C  
April 2010

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IPC-6012D

# Qualification and Performance Specification for Rigid Printed Boards

Developed by the Rigid Printed Board Performance Specifications Task Group (D-33a) of the Rigid Printed Board Committee (D-30) of IPC

***Supersedes:***

IPC-6012C - April 2010

IPC-6012B with

Amendment 1 - July 2007

IPC-6012B - August 2004

IPC-6012A with

Amendment 1 - July 2000

IPC-6012A - October 1999

IPC-6012 - July 1996

IPC-RB-276 - March 1992

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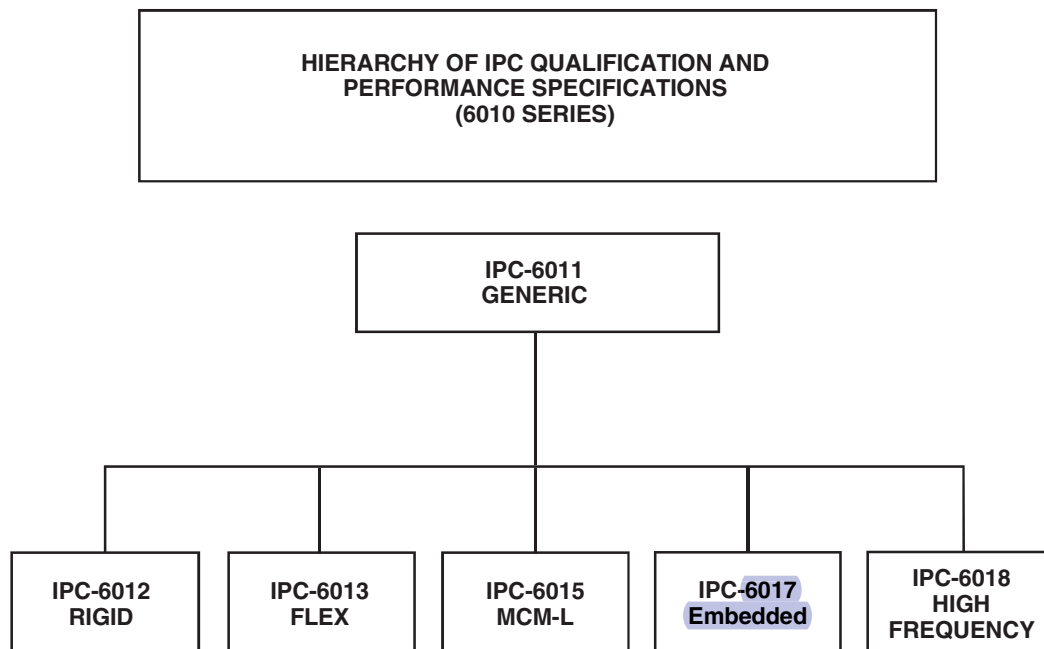
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## FOREWORD

This specification is intended to provide information on the detailed performance criteria of rigid printed boards. It supersedes IPC-6012C and was developed as a revision to those documents. The information contained herein is also intended to supplement the generic requirements identified in IPC-6011. When used together, these documents should lead both manufacturer and customer to consistent terms of acceptability.

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Failure to have all information available prior to building a board may result in a conflict in terms of acceptability.

As technology changes, a performance specification will be updated, or new focus specifications will be added to the document set. The IPC invites input on the effectiveness of the documentation and encourages user response through completion of "Suggestions for Improvement" forms located at the end of each document.

## Acknowledgment

Any document involving a complex technology draws material from a vast number of **sources across many continents**. While the principal members of the Rigid Printed Board Performance Specifications Task Group (D-33a) of the Rigid Printed Board Committee (D-30) are shown below, it is not possible to include all of those who assisted in the evolution of this standard. To each of them, the members of the IPC extend their gratitude.

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# Qualification and Performance Specification for Rigid Printed Boards

## 1 SCOPE

**1.1 Statement of Scope** This specification establishes and defines the qualification and performance requirements for the fabrication of rigid printed boards.

**1.2 Purpose** The purpose of this specification is to provide requirements for qualification and performance of rigid printed boards based on the following constructions and/or technologies. These requirements apply to the finished product unless otherwise specified:

- Single-sided, double-sided printed boards with or without plated-through holes (PTHs).
- Multilayer printed boards with PTHs with or without buried/blind vias/microvias.
- Active/passive embedded circuitry printed boards with distributive capacitive planes and/or capacitive or resistive components.
- Metal core printed boards with or without an external metal heat frame, which may be active or non-active.

**1.2.1 Supporting Documentation** IPC-A-600, which contains figures, illustrations and photographs that can aid in the visualization of externally and internally observable acceptable/nonconforming conditions, may be used in conjunction with this specification for a more complete understanding of the recommendations and requirements.

## 1.3 Performance Classification and Type

**1.3.1 Classification** This specification establishes acceptance criteria for the performance classification of rigid printed boards based on customer and/or end-use requirements. Printed boards are classified by one of three general Performance Classes as defined in IPC-6011.

**1.3.1.1 Requirement Deviations** Requirements deviating from these heritage classifications shall be as agreed between user and supplier (AABUS).

**1.3.1.2 Space Requirement Deviations** Space performance classification deviations are provided in the IPC-6012DS Addendum and are applicable when the addendum is specified within the procurement documentation.

**1.3.2 Printed Board Type** Printed boards without PTHs (Type 1) and with PTHs (Types 2-6) are classified as follows and may include technology adders as described in Table 1-1:

Type 1 — Single-Sided Printed Board

Type 2 — Double-Sided Printed Board

Type 3 — Multilayer Printed Board without blind or buried vias

Type 4 — Multilayer Printed Board with blind and/or buried vias (may include microvias)

Type 5 — Multilayer metal core Printed Board without blind or buried vias

Type 6 — Multilayer metal core Printed Board with blind and/or buried vias (may include microvias)

**1.3.3 Selection for Procurement** Performance class shall be specified in the procurement documentation.

The procurement documentation shall provide sufficient information to fabricate the printed board and ensure that the user receives the desired product. Information that should be included in the procurement documentation is to be in accordance with IPC-2611 and IPC-2614.

The procurement documentation shall specify the thermal stress test method to be used to meet the requirement of 3.6.1. Selection shall be from those depicted in 3.6.1.1, 3.6.1.2 and 3.6.1.3. If not specified (see 5.1), the default shall be per Table 1-2.